Vernissage: New electron-beam micro analysis facilities

21.October 2024

16.15 h, starting in the Studer auditorium

Institute of Geological Sciences

University Bern

We are happy to present our new soft-X-ray detector equipped Electron Probe Microanalyzer (JEOL JXA iSP100) and Field Emission Scanning Electron Microscope ZEISS Sigma 560 with EDS, EBSD, CL and EBIC detectors

We will have a short introduction, tour to visit the instruments followed by a small apéro.

We hope, you all find time to join for this small event.